



February 25-28, 2013
DoubleTree, San Jose



fsim_logic – A VHDL type for testing of FLYTRAP

by

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Presentation Outline

- Background – What was needed and why
- What was readily available and prior work in the area
- The fault simulation types
 - fbit and fsim_logic
 - VHDL packages for fault simulation
- Use of fbit and fsim_logic to address the need
- Conclusions



Background

- What was needed and why
- Working in the area of fault-tolerant design
 - A design where the presence of an incorrect logic value is 'corrected for'
 - Fault occurs due to
 - And intermittent fault –circuit noise, transistor threshold
 - A permanent fault – manufacture or developed over time
- The 'corrected for'
 - Fault is not fixed
 - Fault is mitigated – through detection and redundancy a valid result is generated



Prior work in fault simulation

- During the 1980s fault simulation was a major research focus.
 - A standard set of circuits for evaluation of fault simulator.
 - Many custom simulators – nothing standardized.
- More recent work (2005) – SESC simulator – University of Illinois
 - Architectural evaluation including faults
 - Designs use shadow register to mitigate faults



Modern circuits – HDL Design

- HDLs used for design of embedded systems to complex processors.
- Desire is to have a code version of the HDL that allows fault injection during simulation.
 - Fault injection – A gate evaluation generates the wrong result – probabilistically
 - Allows for control and measurement of the number of faults injected.
 - Faults are injected at the lowest level of design
 - the gates.



Fault tolerant circuits

- Fault tolerant circuit design validation
 - Correct circuit design validation
 - NO ERRORS – typical verification methodologies
 - ERRORS – some gate evaluations result in errors
 - Circuit behavior under error
 - Single Error Detection (SED) circuits – error detected
 - Single Error Correction (SEC/DED) circuits – single errors correct for (output valid) – dual errors detected
 - No error injection – no verification of SEC/DED design



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Prior work in this area

- Work in early 1990s
 - Automatic generation of fixed error HDL models
 - Error location fixed
- Limitations of methodology
 - Large number of fixed error models
 - Limited to fixed location(s) of error
- Not practical for today's design
 - Design with 100,000 gates → 100,000 possible locations for fixed error. (stuck at 0, stuck at 1)



An alternative approach

- VHDL allows for user defined logic types
- A new type
 - Already have bit, std_logic, signed, unsigned, ... (most design in bit, std_logic)
 - Create types fbit, fsim_logic
 - Overload all operators
 - In logic operator evaluation still a table lookup
 - Add a call to a random number generator for fault injection and compare to a threshold.

What the package provides

- The ability to test fault tolerant circuits
 - Error injection is uniformly distributed error injection over all logic operators.
 - Uniform distribution valid as testing operation under error conditions.
 - Number of errors injected can be adjusted to achieve useful results in reasonable simulation time.
 - Distribution of errors over entire design, not fixed location(s).
- Can test any design for behavior under fault conditions. (non-fault-tolerant design)



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Package fbit

- VHDL (and System Verilog) allow for user defined types and overloading of operators.
- fbit corresponds to type bit – fbit is the fault injected version
- Modification to test circuits using fbit
 - Change type declarations from bit to fbit in architecture and ports.
 - Testbench uses type conversion to drive model.



The package declaration

- The declaration
- Logic functions overloaded
- Relational functions overloaded
(=, /=, <, <=, >, >=)
- Type conversion functions

```
-----  
-- Fault Simulation Package -- TYPE fbit (non-resolved)  
-----
```

```
PACKAGE fbit_logic IS
```

```
TYPE fbit IS ('0', -- low  
             '1' -- high );
```

```
-----  
--unconstrained array of fbit  
-----
```

```
TYPE fbit_vector IS ARRAY (NATURAL RANGE <>) of fbit;
```

```
-----  
--Declare logic functions  
-----
```

```
FUNCTION "AND" (l:fbit; r:fbit) RETURN fbit;  
FUNCTION "OR" (l:fbit; r:fbit) RETURN fbit;  
FUNCTION "NAND" (l:fbit; r:fbit) RETURN fbit;  
FUNCTION "NOR" (l:fbit; r:fbit) RETURN fbit;  
FUNCTION "XOR" (l:fbit; r:fbit) RETURN fbit;  
FUNCTION "XNOR" (l:fbit; r:fbit) RETURN fbit;  
FUNCTION "NOT" (l:fbit) RETURN fbit;
```

```
-----  
FUNCTION "AND" (l,r:fbit_vector) RETURN fbit_vector;  
FUNCTION "OR" (l,r:fbit_vector) RETURN fbit_vector;  
FUNCTION "NAND" (l,r:fbit_vector) RETURN fbit_vector;  
FUNCTION "NOR" (l,r:fbit_vector) RETURN fbit_vector;  
FUNCTION "XOR" (l,r:fbit_vector) RETURN fbit_vector;  
FUNCTION "XNOR" (l,r:fbit_vector) RETURN fbit_vector;  
FUNCTION "NOR" (l:fbit_vector) RETURN fbit_vector;
```

```
-----  
CONSTANT threshold : REAL := -.999999;  
impure FUNCTION getrand RETURN real;
```

```
END fbit_logic;
```



Function Evaluation

- Table lookup used: function evaluation and error injection

```
- CONSTANT and_table : fbitlogic_table := (  
- -----  
- --|  0    1  
- -----  
-      ('0', '0'),    -- 0  
-      ('0', '1')   );-- 1  
- FUNCTION "AND" (l,r : fbit) RETURN fbit IS  
-   VARIABLE val : fbit; VARIABLE rnd : REAL;  
- BEGIN  
-   val := and_table(l,r);  
-   rnd : gettrand;  
-   IF (rnd>threshold) THEN  
-       val:=(error_table(val)); END IF;  
-   RETURN (val);  
- END "AND";
```



Error Injection

- Random number generation
 - Impure FUNCTION getrand RETURN real IS
 - VARIABLE vrandval : REAL;
 - BEGIN
 - UNIFORM (seed1,seed2,vrandval);
 - RETURN (vrandval);
 - END getrand;
- The error table
 - CONSTANT error_table : fbit_1d := ('1','0');
- Modification of seeds – variable simulation results

Package fsim_logic

- fsim_logic corresponds to type std_logic – fsim_logic is the fault injected version
 - Also a resolved type
- Modification to test circuits using fsim_logic
 - Change type declarations from std_logic to fsim_logic in architecture and ports.
 - Testbench uses type conversion to drive model.



fsim_logic package declaration

- The declarative part (*initial part*)

```

PACKAGE fsim_logic_1 IS

TYPE fsm_uloic IS ('0', --low
                  '1' --high
                  );

-----
-- unconstrained array of fsm_uloic
-----
TYPE fsm_uloic_vector IS ARRAY (NATURAL RANGE <>) OF fsm_uloic;

-----
-- Resolution Function
-----
FUNCTION resolved (s: fsm_uloic_vector) RETURN fsm_uloic;

-----
-- Declare fault injection fsm_logic type
-----
SUBTYPE fsm_logic IS resolved fsm_uloic;

-----
-- Declare fault injection fsm_logic_vector type
-----
TYPE fsm_logic_vector IS ARRAY (NATURAL RANGE <>) of fsm_logic;

```



fsim_logic is resolved

- No errors injected on resolution
- Resolution table same as std_logic

```

CONSTANT resolution_table : fsimlogic_table := (
--      -----
--      | U    X    0    1    Z    W    L    H    -
--      -----
('U', 'U', 'U', 'U', 'U', 'U', 'U', 'U', 'U'), -- U
('U', 'X', 'X', 'X', 'X', 'X', 'X', 'X', 'X'), -- X
('U', 'X', '0', 'X', '0', '0', '0', '0', 'X'), -- 0
('U', 'X', 'X', '1', '1', '1', '1', '1', 'X'), -- 1
('U', 'X', '0', '1', 'Z', 'W', 'L', 'H', 'X'), -- Z
('U', 'X', '0', '1', 'W', 'W', 'W', 'W', 'X'), -- W
('U', 'X', '0', '1', 'L', 'W', 'L', 'W', 'X'), -- L
('U', 'X', '0', '1', 'H', 'W', 'W', 'H', 'X'), -- H
('U', 'X', 'X', 'X', 'X', 'X', 'X', 'X', 'X') -- -
);

```



Error injection

- Error injection on logical operations
- Methodology the same a fbit
- No error injection for 'U', 'X', 'W', 'Z', '-'

```
CONSTANT error_table : fsimlogic_1d :=  
-- -----  
-- | U      X      0      1      Z      W      L      H      -  
-- -----  
-- ('U', 'X', '1', '0', 'Z', 'W', 'H', 'L', '-') ;
```

The logic functions

- The 'AND' Table

```
--truth table for "and" function
CONSTANT and_table : fsimlogic_table := (
-----
--      | U    X    0    1    Z    W    L    H    -
-----
('U', 'U', '0', 'U', 'U', 'U', '0', 'U', 'U'), -- U
('U', 'X', '0', 'X', 'X', 'X', '0', 'X', 'X'), -- X
('0', '0', '0', '0', '0', '0', '0', '0', '0'), -- 0
('U', 'X', '0', '1', 'X', 'X', '0', '1', 'X'), -- 1
('U', 'X', '0', 'X', 'X', 'X', '0', 'X', 'X'), -- Z
('U', 'X', '0', 'X', 'X', 'X', '0', 'X', 'X'), -- W
('0', '0', '0', '0', '0', '0', '0', '0', '0'), -- L
('U', 'X', '0', 'X', 'X', 'X', '0', '1', 'X'), -- H
('U', 'X', 'X', 'X', 'X', 'X', '0', 'X', 'X') -- -
);
```

- The 'AND' function

```
FUNCTION "and" (l : fsim_ulogic; r : fsim_ulogic) RETURN fsim_ulogic IS
  VARIABLE val : fsim_ulogic;
  VARIABLE rnd : REAL;
BEGIN
  val := and_table(l,r);
  rnd := getrand;
  IF (rnd > threshold) THEN val := (error_table(val)); END IF;
  RETURN (val);
END "and";
```



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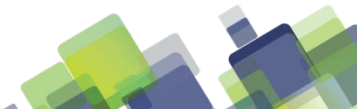
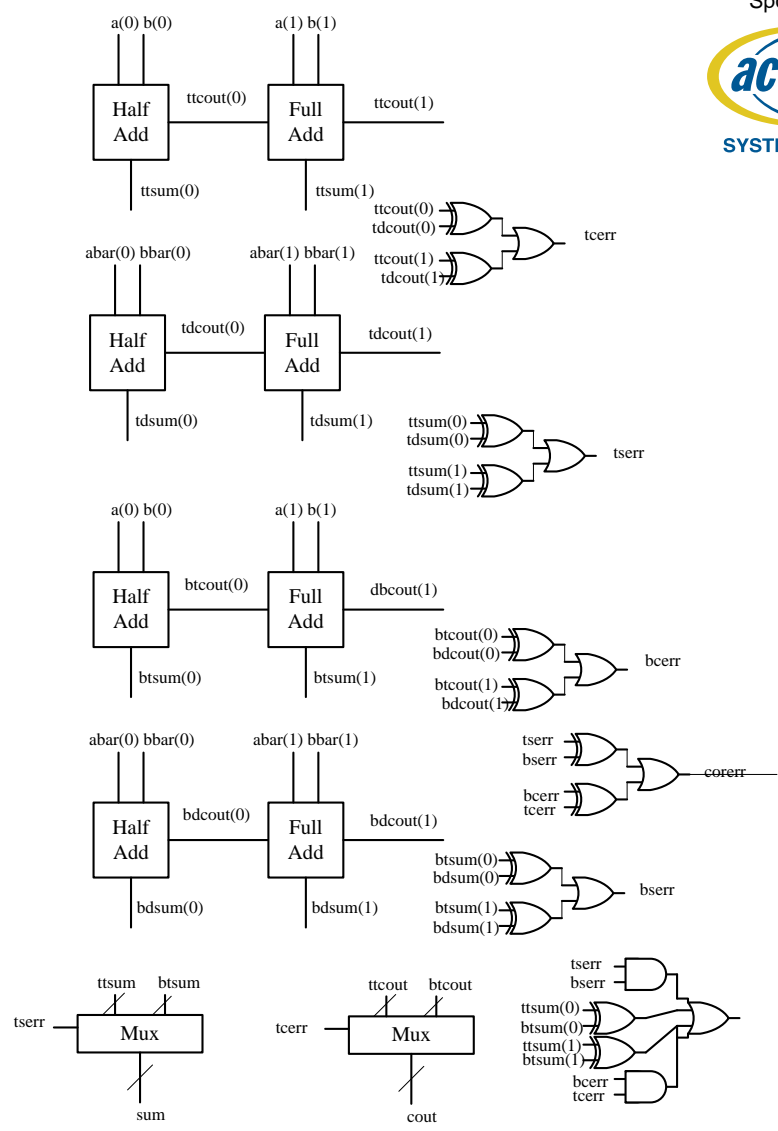
The application of package

- Fault tolerant design
- One of designs – a fault tolerant adder
- 4x replication
 - Provides Single Error Correction and Dual Error Detection (on a bit position by bit position basis)
 - 2x replication – SED
 - 3x replication – SEC (TMR-many space systems)
 - 4x replication – SEC/DED
 - 5x replication – DEC (Space shuttle systems)



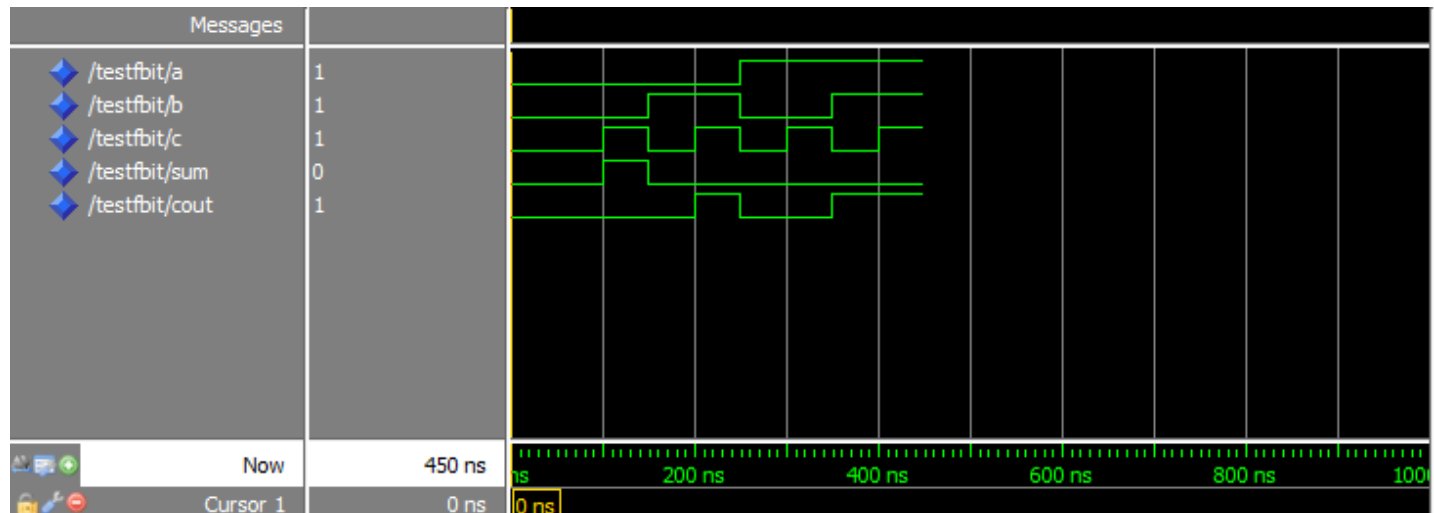
The adder design

- Diagram shows 2 bit positions
- Design is duplicate dual rail
- Why dual rail?



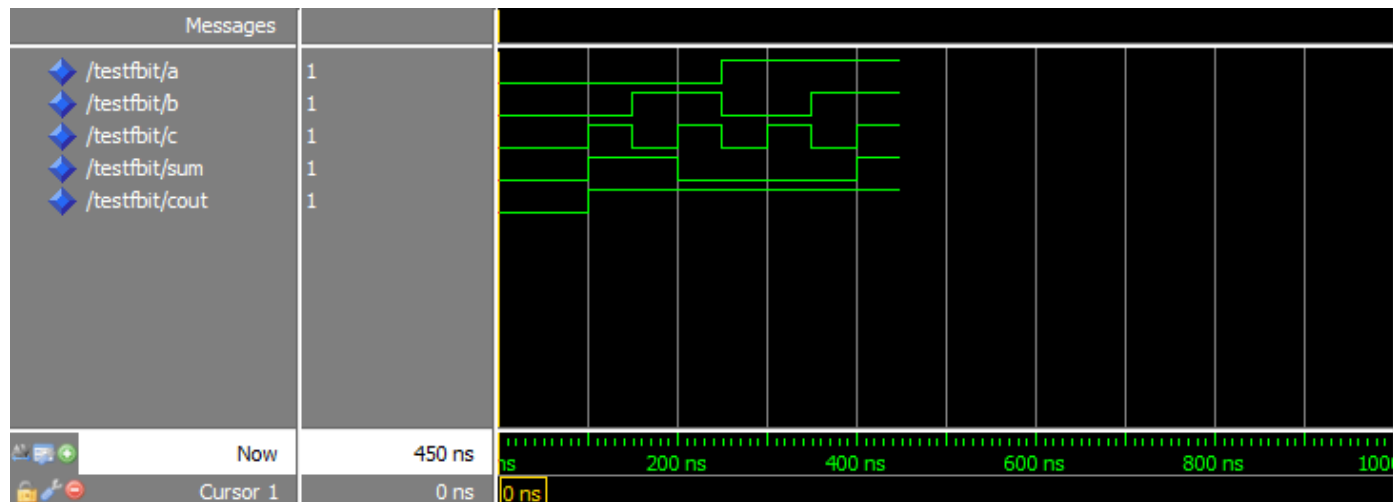
Example of use

- Applied to single full adder
 - Full adder – 6 logic operation evaluations for each test transaction
 - Threshold of .99999 results in no errors



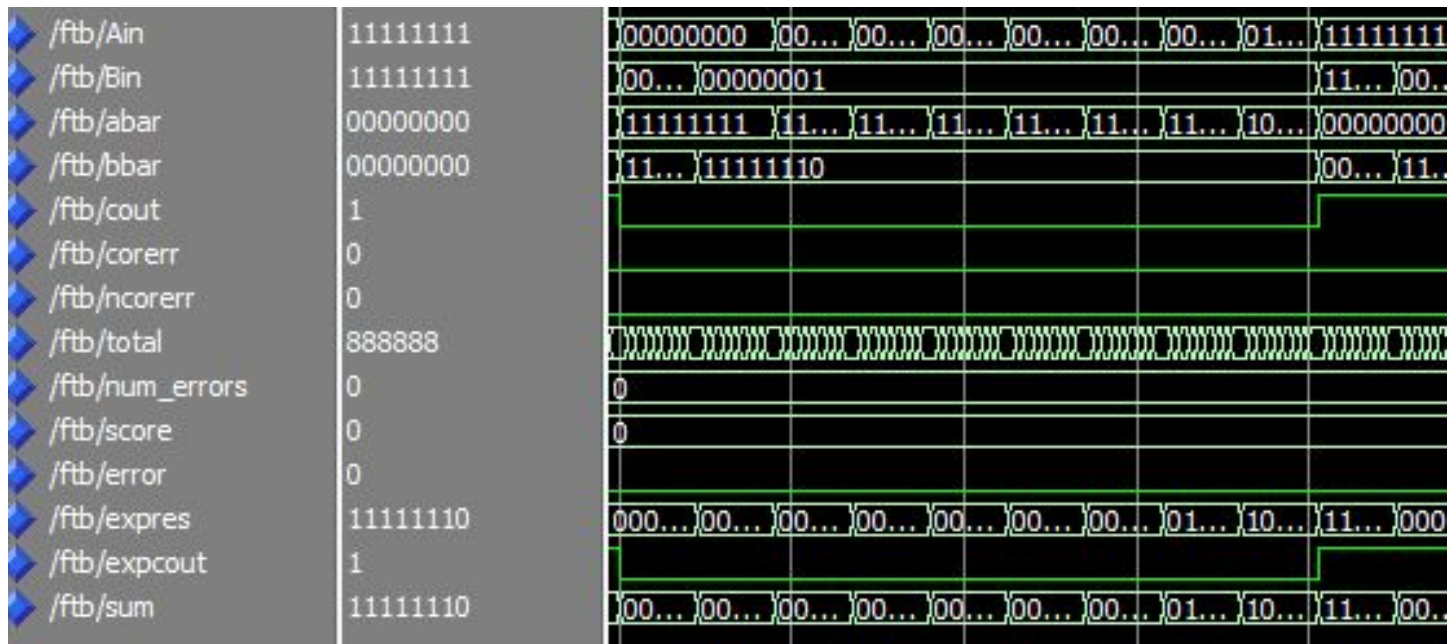
Example of use - errors

- Threshold reset to .9099
- Same design – exhaustive simulation



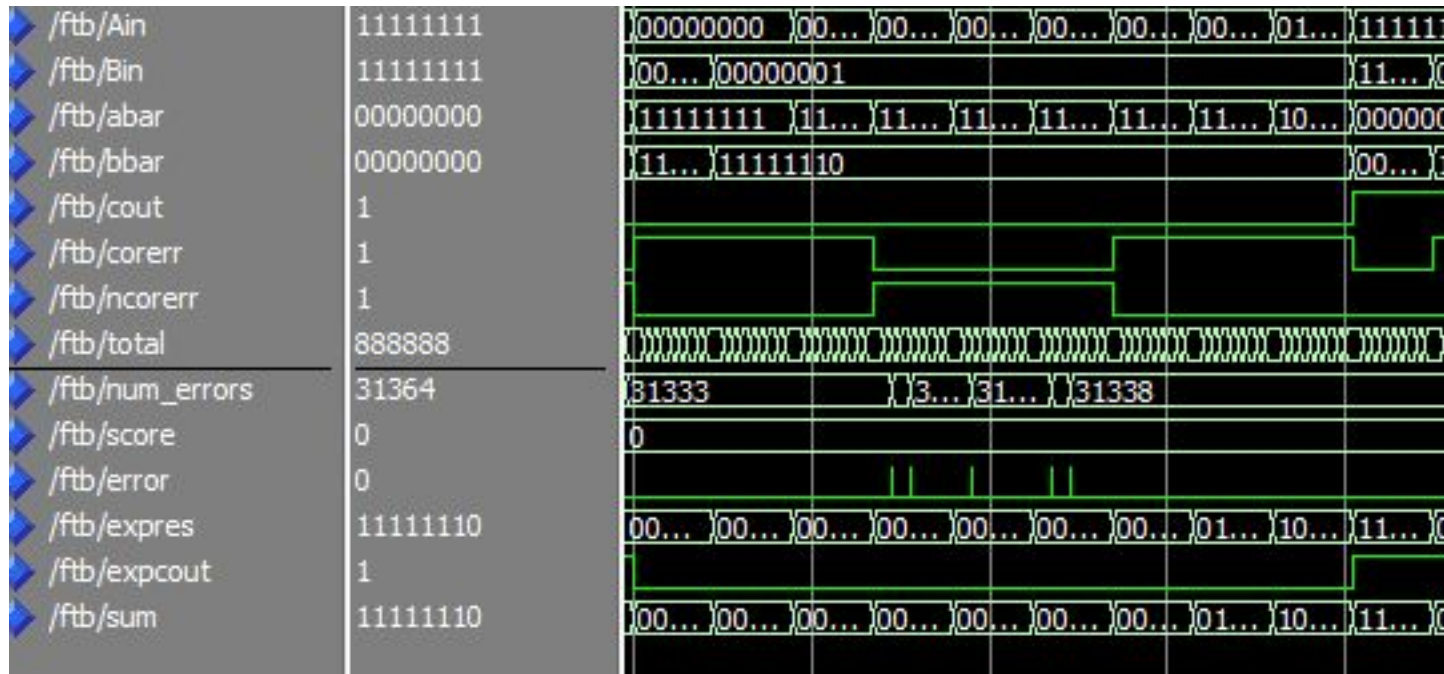
Testing of fault tolerant adder

- Threshold = 1 - no error injection



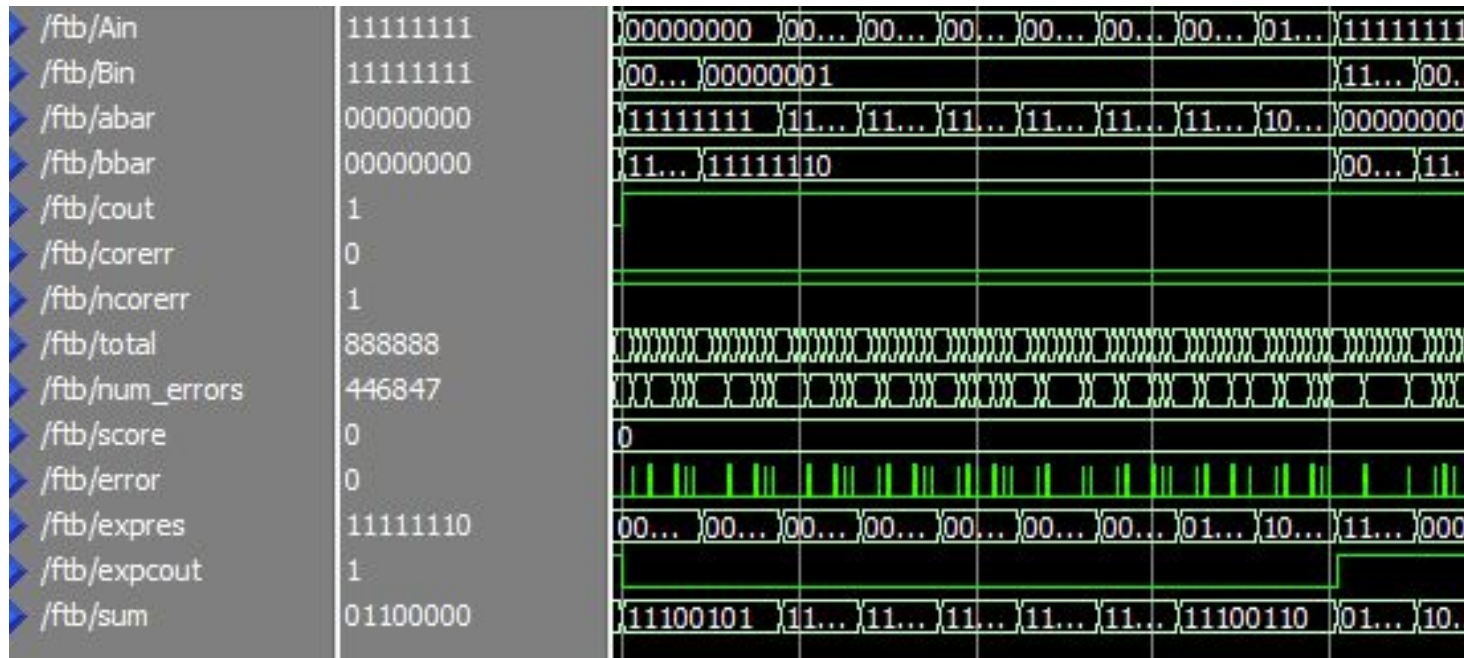
Testing of fault tolerant adder

- Threshold = .99 error injection such that there are non correctable errors.



Testing of fault tolerant adder

- Threshold = 0.70
- Most errors are noncorrectable



Performance overhead

- Fault simulation comes at a cost
 - Simulation overhead time
- Overhead
 - Calls to random number generator
 - Comparison to threshold and error injection



The overhead numbers

- Baseline time come from TYPE bit
- Test of an 8-bit SEC/DED adder

TYPE	threshold	Time	Overhead
Bit	-----	1:03.5	-----
fbit	1.00000	1:16.2	20%
	0.99990	1:16.5	20.4%
	0.99000	1:21.4	28.2%
Std_logic	-----	1.05.5	Vs bit 3%
fsim_logic	1.00000	1:16.0	16.6%
	0.99990	1:16.6	17.5%
	0.99000	1:20.5	23.5%



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Other points

- Before use package itself was verified
 - Package was verified
 - A couple of small errors were found and fixed before package was used.
- Also verified through use on simple designs
 - Individual logic operations
 - Full adder



Single gate performance

- Capability comes at a cost in simulation time and design modification
 - About 20% additional simulation time
 - Small amount of time to modify declaration types





- Questions?

